

University of Groningen

Atomic resolution imaging of light elements in low-dimensional materials

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DOI:
[10.33612/diss.192304075](https://doi.org/10.33612/diss.192304075)

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Document Version
Publisher's PDF, also known as Version of record

Publication date:
2021

[Link to publication in University of Groningen/UMCG research database](#)

Citation for published version (APA):
de Graaf, S. (2021). *Atomic resolution imaging of light elements in low-dimensional materials*. University of Groningen. <https://doi.org/10.33612/diss.192304075>

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Propositions

accompanying the PhD thesis

Atomic resolution imaging of light elements in low-dimensional materials

1. Only by linking the macroscopic world to the microscopic one we can reach a deeper understanding of nature (Chapter 1).
2. Many experimental results can be complicated and confusing, fortunately electron microscopes never lie.
3. Observing light atom dynamics in materials is only possible by balancing imaging accuracy and speed (Chapter 4).
4. Slower electrons are gentler than faster electrons, unless they're not. (Chapter 5).
5. Only the most challenging materials systems reveal the true ability of an imaging method in electron microscopy (Chapter 6).
6. Electron microscopists are only as good as their last specimen (Chapter 3).
7. We do not know where we are stupid until we stick our neck out, and so the whole idea (of science) is to put our neck out. (Richard Feynman)
8. Science communication and sales are not so different: know your product and sell it.

By Sytze de Graaf